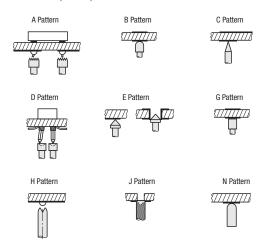
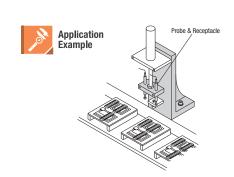
Contact Probes

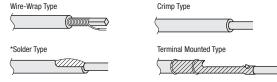
Overview

Contact Probe Tip Shapes & Patterns





Receptacle End Shapes



*Solder Type (C Type and NR68S) will not have a smooth surface and the end receptacles due to its manufacturing method. That will present no problem as long as the probe is pushed in firmly, but the O.D. adjustments are allowed as needed.

General Environmental Conditions

- Operating Temperature 10-40°C. Humidity 30% or Less
- Operating Atmosphere: Free of dust, corrosive gases and oil components etc., where the contact probe may not be contaminated.

Stroke Conditions

- Apply load in the axial direction only. Do not apply lateral load.
- Stroking over the specified stroke (2/3 of full stroke) will significantly decrease the lifetime of the Contact Probe
- Stroking over 60 times per min (constant velocity) may decrease the lifetime of the

Electrical Current Application Conditions

- Apply current only after contact is made and the part is seated.
- Applying current while stroking, with irregular strokes, or in open state where the contact subject is not contacted will severely decrease the lifetime of Contact Probes
- Allowable current shown in the catalog may not be sufficient due to contact probe deterioration. Consider actual applications carefully in the designing stage.

Voltage Application Conditions

- Apply current only after contact is made and the part is seated.
- Do not energize probes in open state (workpiece is not in contact with probes). Discharge before contacting will result in damage to Contact Probes.
- When applying high voltage to a contact probe, be sure to satisfy Electrical Current Application Conditions and Voltage Application Conditions, and be careful of instantaneous large current including discharge.

Allowable Current

 Allowable current provided in the catalog is the maximum continuous current for 1 min, under the following conditions, General Environment, Stroke, Current Application, and Voltage Application Conditions.

Resistance

- Resistance value provided in the catalog is the representative value at rest with 2/3 of full stroke when 10 mA current flows under the following conditions, General Environment, Stroke, Current Application, and Voltage Application Conditions.
- Large current may cause deterioration of contact and inner parts, resulting in resistance value increase
- Stroke cycles repetition may cause deterioration of contact and inner parts, resulting in an increase of resistance value

Replacement Cycle (Reference)

- Replacement Cycle provided in the catalog is the typical value when a probe works properly at 10 mA current under the following conditions, General Environment, Stroke, Current Application, and Voltage Application Conditions
- Replacement cycle can vary depending on operating environment and conditions including resistance increase and spring pressure decrease. Replace Contact Probes considering actual application conditions.

Spring Pressure

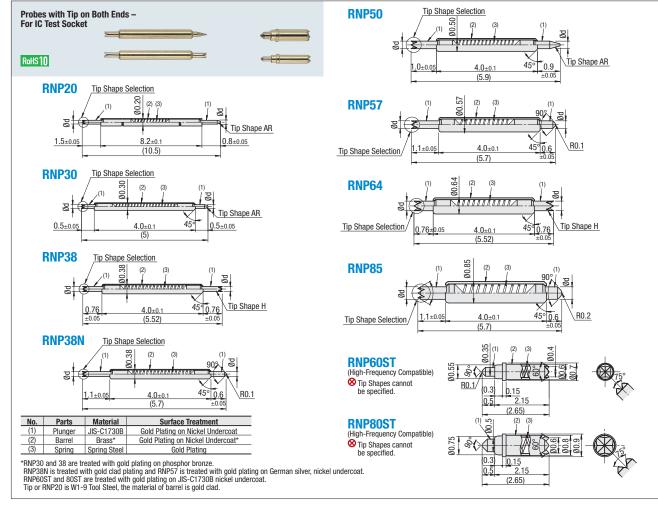
- Spring pressure decreases if temperature of contact probe is higher than 80°C.
- Spring pressure may decrease due to heat generation of a contact probe at larger current.

Mounting Hole for Receptacle (Press-Fit, for Reference Only)

- The values provided are for reference. Appropriate dimensions vary depending on material and thickness of resin plate. Please take the dimensions of receptacle press fit part as a quide for your design.

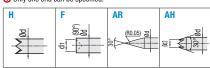
Probes with Tip on Both Ends

For IC Test Socket



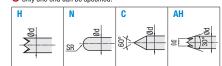
RNP30, RNP38, RNP50, RNP64 Tip Shapes

Only one end can be specified



RNP38N, RNP57, RNP85 Tip Shapes

Only one end can be specified



RNP20 Tip Shapes

Only one end can be specified



		9				
lacement Cycles	d	d ₁	d ₂			

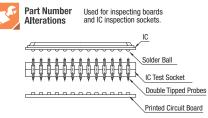
(R0.02)__

Part Number		Mounting Pitch	Full Stroke	Spring Pressure		Allowable	Resistance	Ref. Replacement	4	d	4
Туре	No.	(min.)	(mm)	Initial	2/3 Stroke	Current	nesistance	Usage Cycles	u	d ₁	d ₂
30 38 38 38 50 57 64 85 60	20	0.3 mm	1.3	2 gf	6 gf	0.5 A	300 mΩ	60,000 times	0.12	_	_
	30	0.5 mm	0.8	3 gf	15 gf		60 mΩ	100,000 times	0.15	0.1	0.1
	38		1.0	5 gf	15 gf			200,000 times	0.2	0.15	0.15
	38N		0.98	5 gf	25 gf			100,000 times	0.22	_	0.15
	50	0.8 mm	1.0	3 gf	25 gf	1 A	50 mΩ	200,000 times	0.3	0.2	0.2
	57		0.98	13 gf	30 gf				0.3	_	0.2
	64		1.0	20 gf	30 gf			300,000 times	0.38	0.3	0.25
	85	1.0 mm	0.98	22 gf	35 gf			200,000 times	0.50	_	0.3
	60ST	0.8 mm	0.5	10 gf	25 gf			100,000 times	_		
	T208	1.0 mm	0.5	11 of	20 af						





Features: Since there is continuity at both ends of the probe, ICs themselves can be tested before assembled onto IC boards



Reference: Barrel Hole Diameter Tolerance						
Part Number	Barrel Outside Diameter	Reference Barrel Hole Diameter				
RNP20	0.20	0.22				
RNP30	0.30	0.32				
RNP38	0.38	0.40				
RNP38N	0.38	0.40				
RNP50	0.50	0.52				
RNP57	0.57	0.59				
RNP64	0.64	0.66				
RNP85	0.85	0.87				
RNP60ST	0.6	0.65				
RNP80ST	0.8	0.85				